

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KOBAYASHI ET AL.	
		Examiner Hai V. Nguyen	Art Unit 2142	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,646,755	11-2003	Iwai et al.	358/1.14
*	B	US-7,079,269	07-2006	Teeuwen et al.	358/1.15
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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